

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/777,076 STERN ET AL.	
		Examiner	Art Unit	Page 1 of 1 Thien M. Le 2876

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,587,577	12-1996	Schultz, Darald R.	235/462.44
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ikeda et al., "Two dimensional miniature optical-scanning sensor with silicon micromachined scanning mirror", SPIE 3008, 111.
	V	Kiang et al., "Micromachined microscanners for optical scanning, SPIE 3008,82 (1997)
	W	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.